Listing of the Claims

1. (original) A method of cleaning substrates, comprising the steps of:

> providing a cleaning fluid; forming a supercritical cleaning fluid from said cleaning fluid; and

> contacting the substrate with said supercritical cleaning fluid.

- 2. (original) The method of claim 1 wherein said cleaning fluid is carbon dioxide.
- 3. (original) The method of claim 1 wherein said contacting the substrate with said supercritical cleaning fluid comprises the step of contacting the substrate with said supercritical cleaning fluid for about 5-10 minutes.
- 4. (original) The method of claim 3 wherein said cleaning fluid is carbon dioxide.
- 5. (original) The method of claim 1 further comprising the step

- of mixing a solvent with said cleaning fluid prior to said forming a supercritical cleaning fluid from said cleaning fluid.
- 6. (original) The method of claim 5 wherein said cleaning fluid is carbon dioxide.
- 7. (original) The method of claim 1 wherein said supercritical cleaning fluid is non-conductive.
- 8. (original) The method of claim 1 wherein said cleaning fluid is selected from the group consisting of methane, ethane, propane, ammonia, nitric oxide, fluoromethane and difluoromethane.
- 9. (currently amended) The method of claim 5 [[8]] wherein said solvent is an alcohol.
- 10. (original) The method of claim 1 wherein each of said substrates comprises exposed N-doped and P-doped regions.
- 11. (original) The method of claim 1 wherein each of said substrates comprises an exposed conductive layer.

- 12. (original) The method of claim 11 wherein each of said substrates comprises exposed N-doped and P-doped regions and an exposed conductive layer.
- 13. (original) A method of cleaning a substrate, comprising the steps of:

providing fluid carbon dioxide;

forming a supercritical carbon dioxide from said fluid carbon dioxide; and

contacting the substrate with said supercritical carbon dioxide.

- 14. (original) The method of claim 13 further comprising the step of mixing a solvent with said fluid carbon dioxide to define a fluid mixture prior to said forming a supercritical carbon dioxide from said fluid carbon dioxide.
- 15. (original) The method of claim 13 wherein said supercritical carbon dioxide is non-conductive.

- 16. (original) The method of claim 13 wherein said substrate comprises exposed N-doped and P-doped regions and an exposed conductive layer.
- 17. (currently amended) A method of cleaning a substrate, comprising the steps of:

providing a cleaning fluid selected from the group consisting of <u>carbon dioxide</u>, methane, ethane, propane, ammonia, nitric oxide, fluoromethane and difluoromethane;

forming a supercritical cleaning fluid from said cleaning fluid; and

contacting the substrate with said supercritical cleaning fluid.

- 18. (original) The method of claim 17 further comprising the step of mixing a solvent with said cleaning fluid to define a fluid mixture prior to said forming a supercritical cleaning fluid from said cleaning fluid.
- 19. (original) The method of claim 17 wherein said supercritical

cleaning fluid is non-conductive.

20. (original) The method of claim 17 wherein said substrate comprises exposed N-doped and P-doped regions and an exposed conductive layer.